

Notic of References Cited

Application/Control No.

10/037,971

Applicant(s)/Patent Under
Reexamination
STEINBERG ET AL.

Examiner

Scott A Knauss

Art Unit

2874

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,474,878	11-2002	Demangone, Drew A.	385/78
	B	US-4,998,796	03-1991	Bonanni et al.	385/83
	C	US-4,818,059	04-1989	Kakii et al.	385/65
	D	US-5,574,817	11-1996	Henson et al.	385/114
	E	US-5,257,334	10-1993	Takahashi, Mitsuo	385/65
	F	US-5,815,621	09-1998	Sakai et al.	385/80
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06027343 A	02-1994	Japan	YAMADA et al.	G02B 06/24
	O	JP 04043308 A	02-1992	Japan	ISHIDA et al.	G02B 06/36
	P	JP 08054519 A	02-1996	Japan	KASHIWAZAKI, AKIRA	G02B 06/00
	Q	JP 03061916 A	03-1991	Japan	MIYAZAKI et al.	G02B 06/36
	R	JP 10048477 A	02-1998	Japan	SUDA et al.	G02B 06/40
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

8/4/04